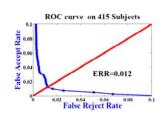
# **IEEE Second International Conference on**

# Biometrics: Theory, Applications and Systems











The *IEEE Second International Conference on Biometrics: Theory, Applications and Systems (BTAS 08)* is the premier research meeting focused on biometrics. Its broad scope includes advances in fundamental pattern recognition techniques relevant to biometrics, new algorithms and / or technologies for biometrics, analysis of specific applications, and analysis of the social impacts of biometrics technology. Areas of coverage include biometrics based on voice, fingerprint, iris, face, handwriting, gait and other modalities, as well as multi-modal biometrics and new biometrics based on novel sensing technologies. Submissions will be rigorously reviewed, and should clearly make the case for a documented improvement over the existing state of the art. Experimental results for contributions in established areas such as voice, face, iris, fingerprint, and gait are encouraged to use the largest and most challenging existing publicly available datasets. Topics of interest include but are not limited to:

security and privacy recognition by gait
ear biometrics palm / foot print
hand geometry fingerprint
smart guns anti-spoofing methods
face appearance illumination-invariance
performance evaluation novel applications

face recognition iris biometrics
multi-biometric fusion
speaker recognition
age effects covariate analysis
social impact analysis

iris biometrics
3D face recognition
writer recognition
feature analysis
new classifiers
usability studies

**Conference Venue.** BTAS 08 will be held at the Hyatt Regency Crystal City, convenient to numerous dining, shopping, and tourist attractions. Families should enjoy visiting Washington DC at this time of year.

## **Important Dates.**

Paper submission – May 16, 2008. Decision notification – July 25, 2008. Final copy due – August 15, 2008. BTAS 08 begins – Mon., Sept. 29, 2008. BTAS 08 ends – Wed., October 1, 2008. **Submissions.** Submitted papers may not have been accepted elsewhere, or be under review elsewhere, during the BTAS 08 review period. BTAS is sponsored by the IEEE Systems, Man and Cybernetics Society. Papers accepted and presented at the conference will appear in the IEEE Xplore digital library. Papers may be up to six pages in conference paper format. Details will be available at http://www.cse.nd.edu/BTAS\_08/.

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